

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10582150	HIPP, IMRE
Examiner	Art Unit	
HOON J CHUNG	2416	

SEARCHED

Class	Subclass	Date	Examiner
370	204-205, 516-520	05/04/2009	HJC
375	356, 362, 364, 373, 375, 377	05/04/2009	HJC

SEARCH NOTES

Search Notes	Date	Examiner
Double Patenting	05/04/2009	HJC
EAST (PLL, reference clock, TDM, etc.)	05/04/2009	HJC
	05/05/2009	
Google (PLL, reference clock, synchronization, etc.)	05/04/2009	HJC
Consulted an examiner (Habte Mered)	05/04/2009	HJC

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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Examiner.Alt Unit 2416